## Application/Control No. Applicant(s)/Patent Under Reexamination NAH ET AL. Examiner Dennis-Doon Chow Applicant(s)/Patent Under Reexamination NAH ET AL. Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,590,553	07-2003	Kimura et al.	345/92
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	F	US-			
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## **NON-PATENT DOCUMENTS**

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